

Supplementary information

Chemical manipulation of phase stability and electronic behavior in $\text{Cu}_{4-x}\text{Ag}_x\text{Se}_2$

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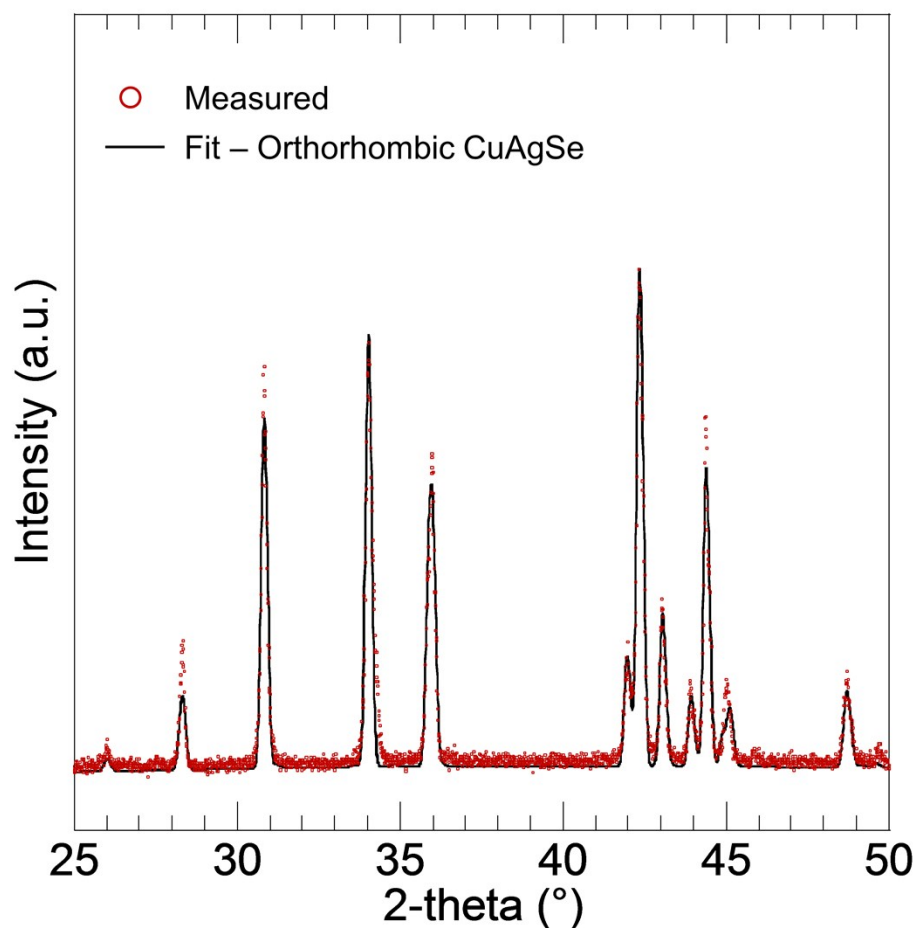


Figure S1 Profile fitting of CuAgSe using Orthorhombic CuAgSe (S.G. P mnm).

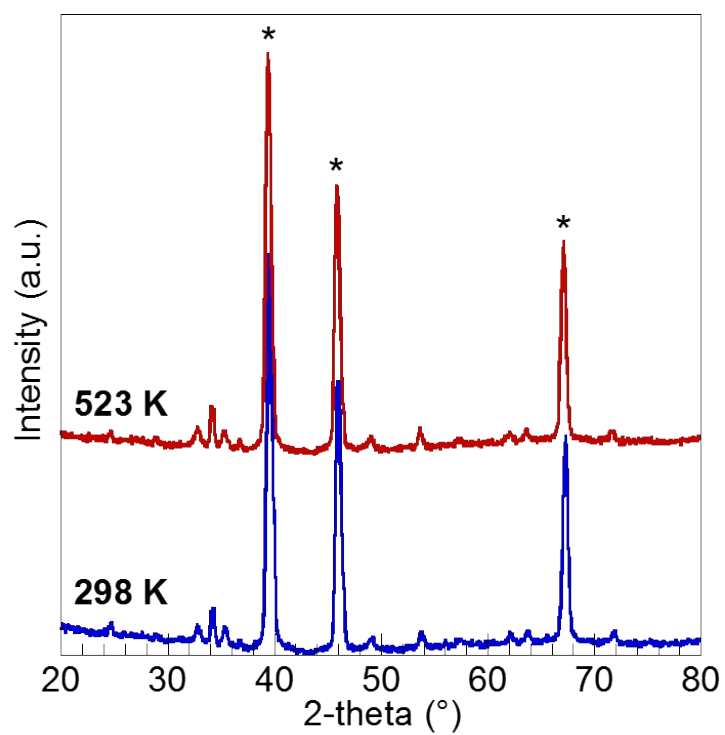


Figure S2 Temperature-dependent X-ray diffraction of the high-temperature platinum holder. Peaks marked by an asterisk (*) belong to the platinum holder, where other peaks are unidentified, but a part of the holder background.

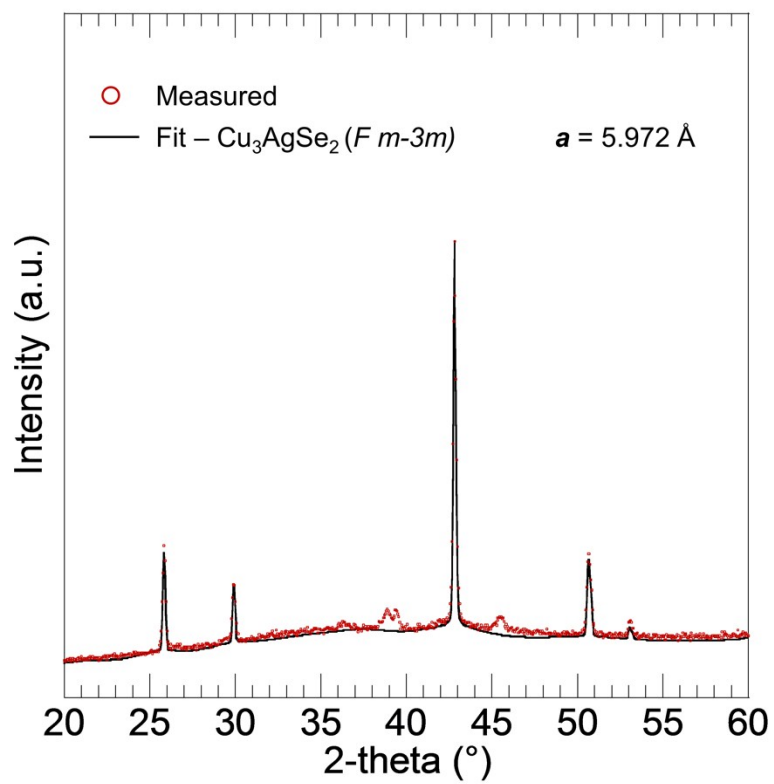


Figure S3 Profile fitting of Cu_3AgSe_2 using Orthorhombic CuAgSe (S.G. $Fm-3m$).

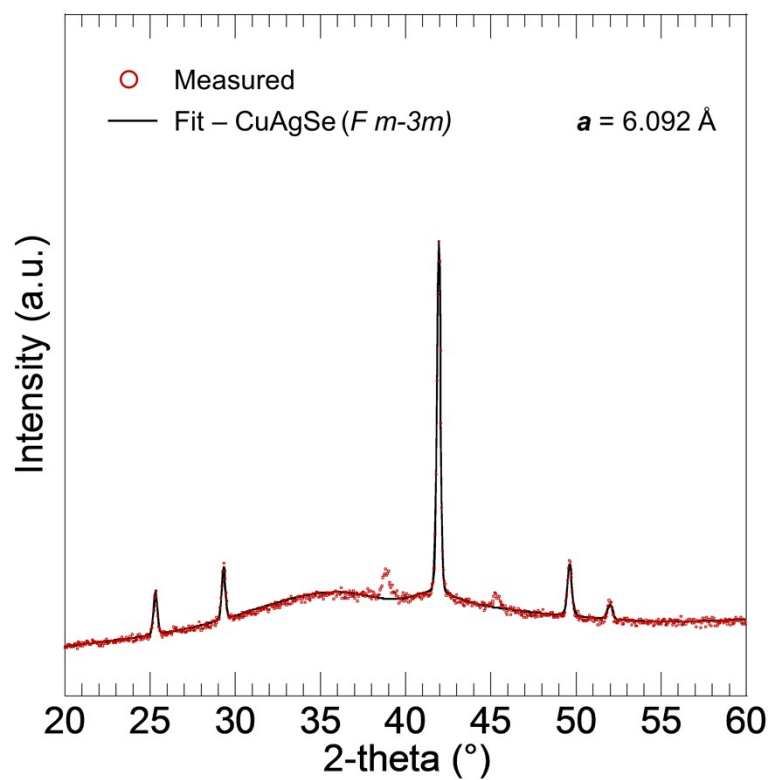


Figure S4 Profile fitting of CuAgSe using cubic CuAgSe (S.G. Fm-3m).

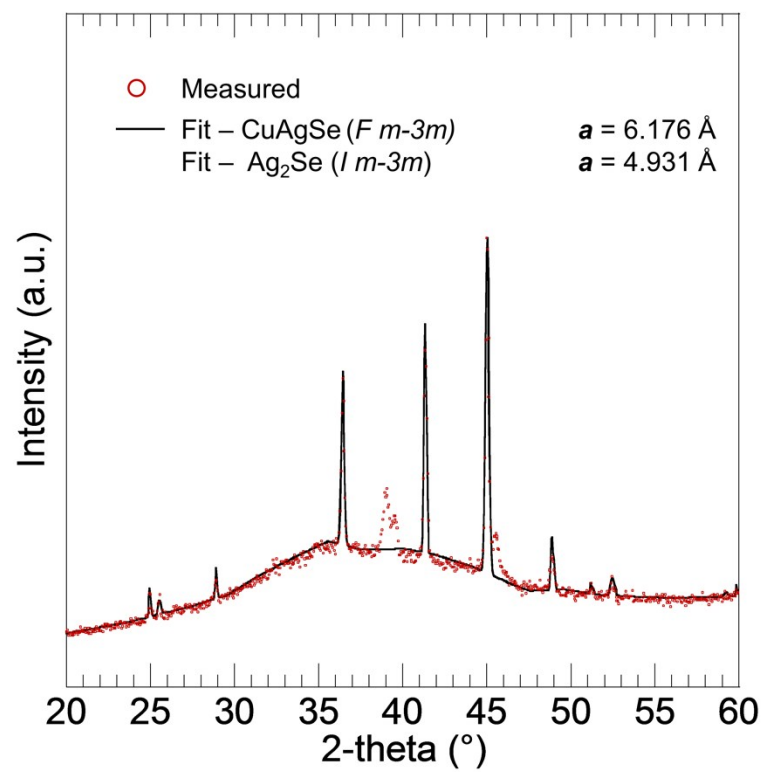


Figure S5 Profile fitting of CuAg_3Se_2 using cubic CuAgSe (S.G. $Fm\bar{3}m$) and cubic Ag_2Se (S.G. $I\bar{4}3m$)